

## 74ABT16374 16-Bit D-Type Flip-Flop with 3-STATE Outputs

### General Description

The ABT16374 contains sixteen non-inverting D-type flip-flops with 3-STATE outputs and is intended for bus oriented applications. The device is byte controlled. A buffered clock (CP) and Output Enable ( $\overline{OE}$ ) are common to each byte and can be shorted together for full 16-bit operation.

### Features

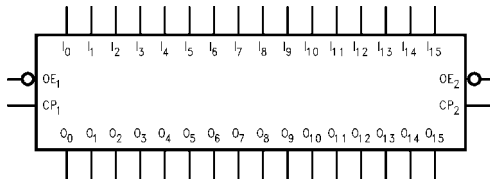
- Separate control logic for each byte
- 16-bit version of the ABT374
- Edge-triggered D-type inputs
- Buffered Positive edge-triggered clock
- High impedance glitch free bus loading during entire power up and power down cycle
- Non-destructive hot insertion capability
- Guaranteed latch-up protection

### Ordering Code:

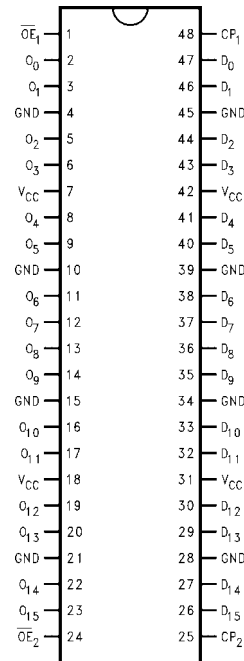
Order Number	Package Number	Package Description
74ABT16374CSSC	MS48A	48-Lead Small Shrink Outline Package (SSOP), JEDEC MO-118, 0.300" Wide
74ABT16374CMTD	MTD48	48-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide

Devices also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code.

### Logic Symbol



### Connection Diagram



### Pin Descriptions

Pin Name	Description
$\overline{OE}_n$	3-STATE Output Enable Input (Active LOW)
CP <sub>n</sub>	Clock Pulse Input (Active Rising Edge)
D <sub>0</sub> -D <sub>15</sub>	Data Inputs
O <sub>0</sub> -O <sub>15</sub>	3-STATE Outputs

## Functional Description

The ABT16374 consists of sixteen edge-triggered flip-flops with individual D-type inputs and 3-STATE true outputs. The device is byte controlled with each byte functioning identically, but independent of the other. The control pins can be shorted together to obtain full 16-bit operation. Each byte has a buffered clock and buffered Output Enable common to all flip-flops within that byte. The description which follows applies to each byte. Each flip-flop will store the state of their individual D inputs that meet the setup and hold time requirements on the LOW-to-HIGH Clock ( $CP_n$ ) transition. With the Output Enable ( $\overline{OE}_n$ ) LOW, the contents of the flip-flops are available at the outputs. When  $\overline{OE}_n$  is HIGH, the outputs go to the high impedance state. Operation of the  $OE_n$  input does not affect the state of the flip-flops.

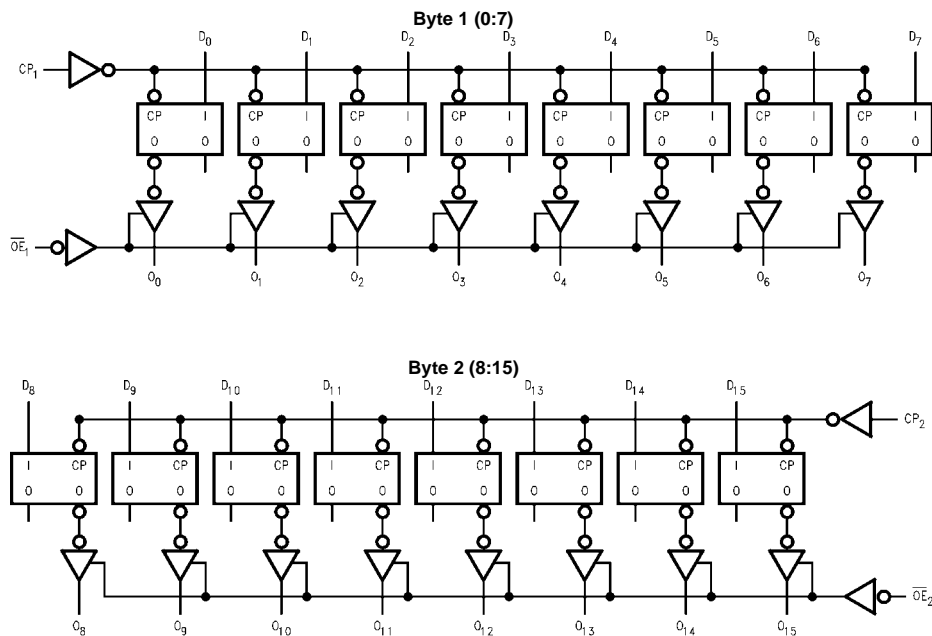
## Truth Tables

Inputs			Outputs
$CP_1$	$\overline{OE}_1$	$D_0-D_7$	$O_0-O_7$
↗	L	H	H
↗	L	L	L
L	L	X	(Previous)
X	H	X	Z

Inputs			Outputs
$CP_2$	$\overline{OE}_2$	$D_8-D_{15}$	$O_8-O_{15}$
↗	L	H	H
↗	L	L	L
L	L	X	(Previous)
X	H	X	Z

H = HIGH Voltage Level  
 L = LOW Voltage Level  
 X = Immaterial  
 Z = High Impedance

## Logic Diagrams



Absolute Maximum Ratings <sup>(Note 1)</sup>		Recommended Operating Conditions	
Storage Temperature	-65°C to +150°C	Free Air Ambient Temperature	-40°C to +85°C
Ambient Temperature under Bias	-55°C to +125°C	Supply Voltage	+4.5V to +5.5V
Junction Temperature under Bias	-55°C to +150°C	Minimum Input Edge Rate ( $\Delta V/\Delta t$ )	
V <sub>CC</sub> Pin Potential to Ground Pin	-0.5V to +7.0V	Data Input	50 mV/ns
Input Voltage (Note 2)	-0.5V to +7.0V	Enable Input	20 mV/ns
Input Current (Note 2)	-30 mA to +5.0 mA	Clock Input	100mV/ns
Voltage Applied to Any Output in the Disabled or Power-Off State	-0.5V to 5.5V		
in the HIGH State	-0.5V to V <sub>CC</sub>		
Current Applied to Output in LOW State (Max)	twice the rated I <sub>OL</sub> (mA)		
DC Latchup Source Current:			
$\overline{OE}$ Pin	-350 mA		
(Across Comm Operating Range)			
Other Pins	-500 mA		
Over Voltage Latchup (I/O)	10V		

**Note 1:** Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

**Note 2:** Either voltage limit or current limit is sufficient to protect inputs.

## DC Electrical Characteristics

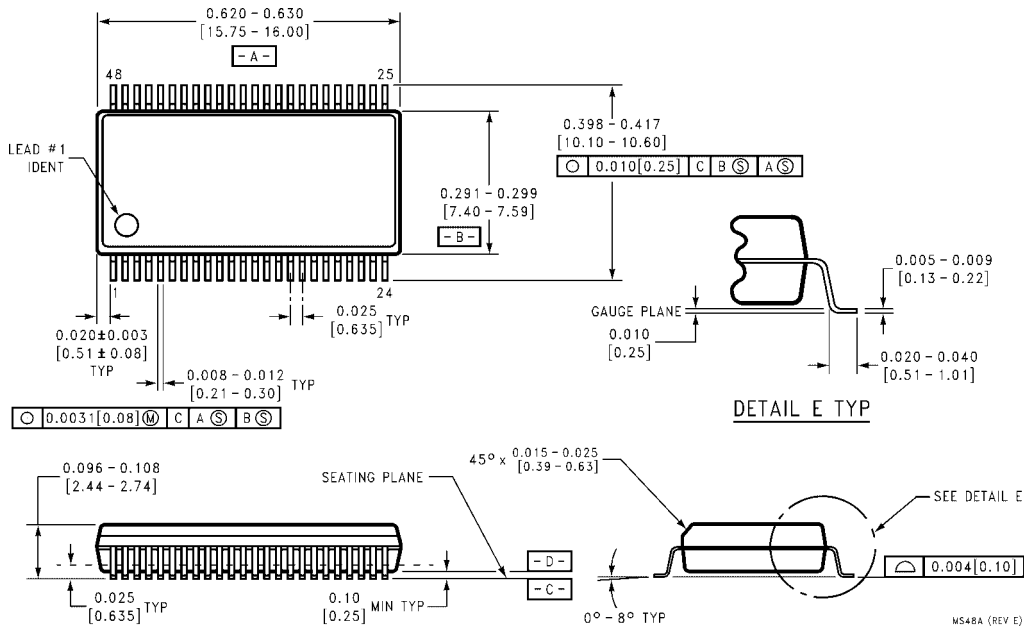
Symbol	Parameter	Min	Typ	Max	Units	V <sub>CC</sub>	Conditions
V <sub>IH</sub>	Input HIGH Voltage	2.0			V		Recognized HIGH Signal
V <sub>IL</sub>	Input LOW Voltage			0.8	V		Recognized LOW Signal
V <sub>CD</sub>	Input Clamp Diode Voltage			-1.2	V	Min	I <sub>N</sub> = -18 mA
V <sub>OH</sub>	Output HIGH Voltage	2.5			V	Min	I <sub>OH</sub> = -3 mA
		2.0			V	Min	I <sub>OH</sub> = -32 mA
V <sub>OL</sub>	Output LOW Voltage		0.55		V	Min	I <sub>OL</sub> = 64 mA
I <sub>IH</sub>	Input HIGH Current		1	1	μA	Max	V <sub>IN</sub> = 2.7V (Note 3) V <sub>IN</sub> = V <sub>CC</sub>
I <sub>BVI</sub>	Input HIGH Current Breakdown Test			7	μA	Max	V <sub>IN</sub> = 7.0V
I <sub>IL</sub>	Input LOW Current		-1	-1	μA	Max	V <sub>IN</sub> = 0.5V (Note 3) V <sub>IN</sub> = 0.0V
V <sub>ID</sub>	Input Leakage Test	4.75			V	0.0	I <sub>ID</sub> = 1.9 μA All Other Pins Grounded
I <sub>OZH</sub>	Output Leakage Current		10		μA	0-5.5V	V <sub>OUT</sub> = 2.7V; $\overline{OE}$ = 2.0V
I <sub>OZL</sub>	Output Leakage Current		-10		μA	0-5.5V	V <sub>OUT</sub> = 0.5V; $\overline{OE}$ = 2.0V
I <sub>OS</sub>	Output Short-Circuit Current	-100		-275	mA	Max	V <sub>OUT</sub> = 0.0V
I <sub>CEX</sub>	Output HIGH Leakage Current			50	μA	Max	V <sub>OUT</sub> = V <sub>CC</sub>
I <sub>ZZ</sub>	Bus Drainage Test			100	μA	0.0	V <sub>OUT</sub> = 5.5V; All Others V <sub>CC</sub> or GND
I <sub>CCH</sub>	Power Supply Current		2.0		mA	Max	All Outputs HIGH
I <sub>CCL</sub>	Power Supply Current		62		mA	Max	All Outputs LOW
I <sub>CCZ</sub>	Power Supply Current		2.0		mA	Max	$\overline{OE}$ = V <sub>CC</sub> ; All Others at V <sub>CC</sub> or GND
I <sub>CC1</sub>	Additional I <sub>CC</sub> /Input		2.5	2.5	mA	Max	V <sub>I</sub> = V <sub>CC</sub> - 2.1V Enable Input V <sub>I</sub> = V <sub>CC</sub> - 2.1V Data Input V <sub>I</sub> = V <sub>CC</sub> - 2.1V All Others at V <sub>CC</sub> or GND
			2.5	2.5	mA	Max	
			2.5	2.5	mA	Max	
I <sub>CCD</sub>	Dynamic I <sub>CC</sub> (Note 3)		No Load	0.30	mA/ MHz	Max	Outputs Open $\overline{OE}$ = GND, (Note 4) One Bit Toggling, 50% Duty Cycle

**Note 3:** Guaranteed, but not tested.

**Note 4:** For 8-bit toggling, I<sub>CCD</sub> < 0.8 mA/MHz.

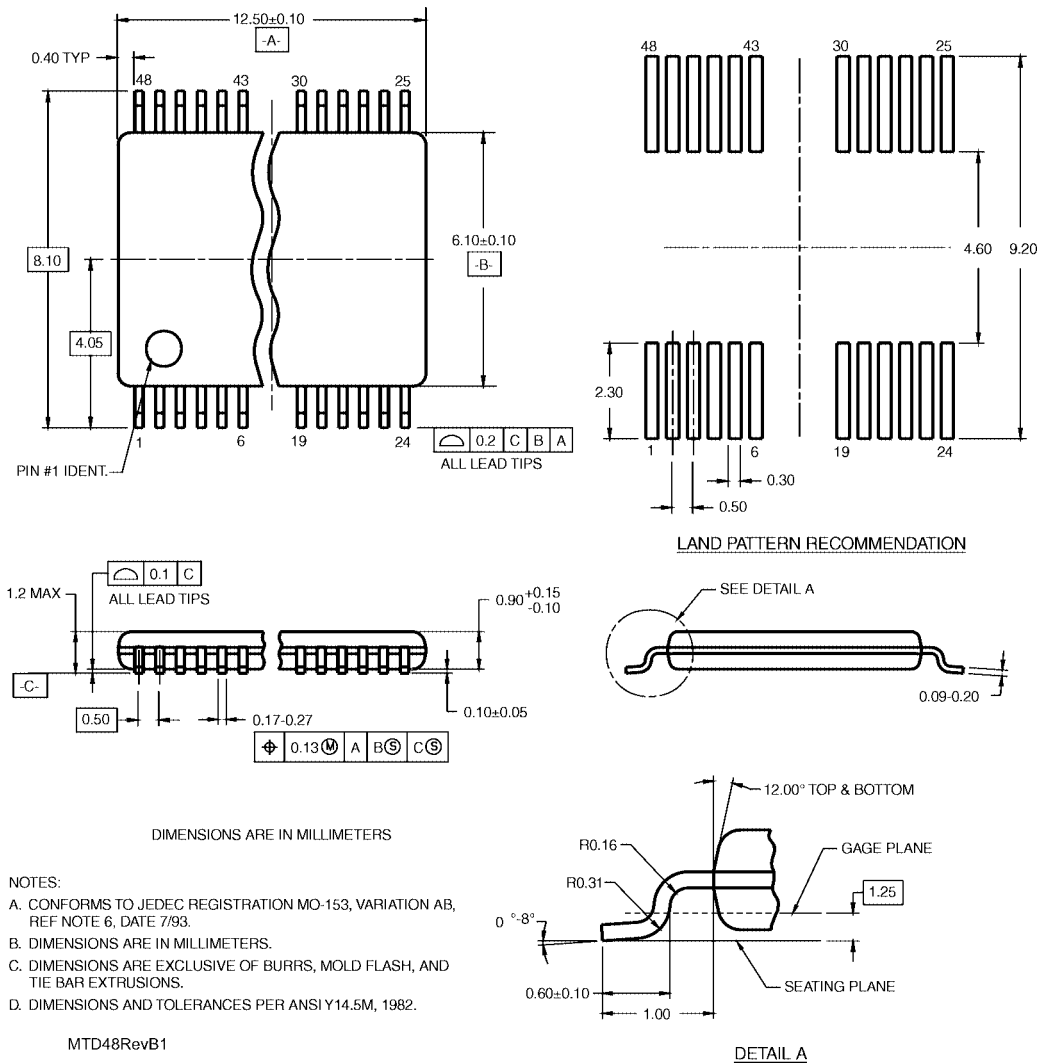
AC Electrical Characteristics							
(SSOP Package)							
Symbol	Parameter	T <sub>A</sub> = +25°C V <sub>CC</sub> = +5.0V C <sub>L</sub> = 50 pF			T <sub>A</sub> = -40°C to +85°C V <sub>CC</sub> = 4.5V to 5.5V C <sub>L</sub> = 50 pF		Units
		Min	Typ	Max	Min	Max	
t <sub>MAX</sub>	Maximum Clock Frequency	150			150		MHz
t <sub>PLH</sub>	Propagation Delay	1.8		6.2	1.8	6.2	ns
t <sub>PHL</sub>	CP to O <sub>n</sub>	1.8		5.9	1.8	5.9	
t <sub>PZH</sub>	Output Enable Time	1.2		5.6	1.2	5.6	ns
t <sub>PZL</sub>		1.6		5.3	1.6	5.3	
t <sub>PHZ</sub>	Output Disable Time	2.2		7.1	2.2	7.1	ns
t <sub>PLZ</sub>		2.2		6.6	2.2	6.6	
AC Operating Requirements							
Symbol	Parameter	T <sub>A</sub> = +25°C V <sub>CC</sub> = +5.0V C <sub>L</sub> = 50 pF		T <sub>A</sub> = -40°C to +85°C V <sub>CC</sub> = 4.5V to 5.5V C <sub>L</sub> = 50 pF		Units	
		Min	Max	Min	Max		
t <sub>S</sub> (H)	Setup Time, HIGH	1.1		1.1		ns	
t <sub>S</sub> (L)	or LOW D <sub>n</sub> to CP	1.1		1.1			
t <sub>H</sub> (H)	Hold Time, HIGH	1.3		1.3		ns	
t <sub>H</sub> (L)	or LOW D <sub>n</sub> to CP	1.3		1.3			
t <sub>W</sub> (H)	Pulse Width, CP	3.0		3.0		ns	
t <sub>W</sub> (L)	HIGH or LOW	3.0		3.0			
Capacitance							
Symbol	Parameter	Typ	Units	Conditions (T <sub>A</sub> = 25°C)			
C <sub>IN</sub>	Input Capacitance	5.0	pF	V <sub>CC</sub> = 0V			
C <sub>OUT</sub> (Note 5)	Output Capacitance	11.0	pF	V <sub>CC</sub> = 5.0V			
<b>Note 5:</b> C <sub>OUT</sub> is measured at frequency f = 1 MHz, per MIL-STD-883, Method 3012.							

**Physical Dimensions** inches (millimeters) unless otherwise noted



**48-Lead Small Shrink Outline Package (SSOP), JEDEC MO-118, 0.300" Wide  
Package Number MS48A**

**Physical Dimensions** inches (millimeters) unless otherwise noted (Continued)



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